



Form 1449 (Modified) Information Disclosure Statement By Applicant (Use Several Sheets if Necessary)	Atty Docket No. ICONP006 Applicant: Seo et al. Filing Date September 12, 2003	Application No.: 10/661,385 Group 3723
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U.S. Patent Documents

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
	A						
	B						
	C						
	D						
	E						
	F						
	G						
	H						
	I						

Foreign Patent or Published Foreign Patent Application

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
							Yes	No
DVN	J	WO 02/085573 A1	10-31-02	PCT				
	K							
	L							
	M							
	N							

Other Documents

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
	O	
	P	
	Q	
Examiner	<i>Dung van Nguyen</i>	
	Date Considered <i>1-17-2006</i>	

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



Form 1495A (Revised) Information Disclosure Statement By Applicant (Use Several Sheets if Necessary)	Atty Docket No.	Application No.:
	ICONP006	10/661,385
	Applicant:	
	Seo et al.	
Filing Date	Group	
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	J							
	K							
	L							
	M							
	N							

Other Documents

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
DVN	O	Letter from Intercon Technology, Inc. regarding Semicon Taiwan 2002, dated August 23, 2002. ✓
DVN	P	Dean et al., "New Fine-Beam, Abrasive Water Jet Technology Enables Photonic and Small Device Singulation" Chip Scale Review, August/September 2002. ✓
	Q	
Examiner	Date Considered	
<i>Dung van Nguyen</i>	1-17-2006	

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